

PATENT APPLICATION

TITLE:

Method for real-time control of the fabrication of a thin-film structure by ellipsometric measurement

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L'EXPLOITATION DES PROCEDES GEORGES CLAUDE**

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ABSTRACT

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B1
Method for real-time control of the fabrication of a thin-film structure comprising a substrate by ellipsometric measurement in which:

- variables directly linked to the ellipsometric ratio $\rho = \tan\Psi \exp(i\Delta)$ are measured; and
- the said variables are compared with reference values.

The comparison relates to the length of the path traveled at a time t in the plane of the variables with respect to an initial point at time t_0 , for each layer participating in the thin-film structure.

Figure 2